Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/691,212	DORNBUSCH ET AL.	
Examiner	Art Unit	_
Chris C. Chu	2815	

SEARCHED						
Class	Subclass	Date	Examiner			
257	E23.079, E23.052, 786 & 778	9/14/2006	C.C.			
257	686	9/14/2006	C.C.			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/14/2006	C.C.		
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